

Complex satellite metrology

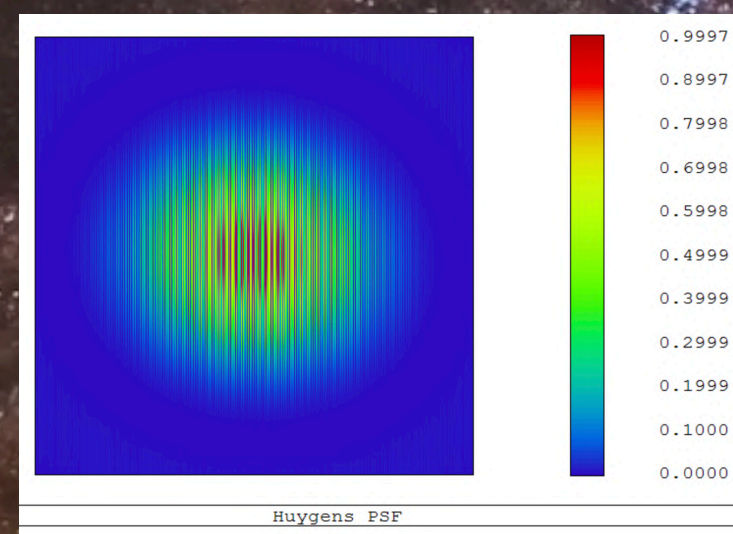
- Measurement and analysis of systematic variations in Gaia
- Basic Angle Monitoring Device
- Long term analysis
- Picoradian effects modelization
- Applied Fourier analysis
- Data mining

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International and multidisciplinary
team experience

